Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/674,616	YOUN, JEONGNAM	
Examiner	Art Unit	
Tan V. Mai	2193	

	SEARCHED					
Class	Subclass	Date	Examiner			
708	402	7/5/2006	MAI			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor search Double Patenting Check Data Bases Search (see search history printout)	7/5/2006	MAI		
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